Environmental Scanning Electron Microscope (SEM/ESEM)	Model: Unit and Room: Responsible: Further information:		Quanta 250 FEG (FEI) ZfN, Albertstraße 23,back building, basement, room nr. 9 Dr. Yi Thomann Dr. Ralf Thomann http://www.fmf.uni-freiburg.de/service/ dienstleistungen/mikroskopie/index_htm/
Short Description:		Picture of the Equipment	
SEM/ESEM machine with field er and analytical EDX system Available Experiments/Technique SEM measurements under high- vacuum conditions, and resolution about 1.5nm. The machine allow gaseous environment in the spec chamber up to pressures of 4000 observation of biological or medic in their natural state. The microscope is equipped with EDX system for elemental analys	ues: - and low- ions down to ows a watery ecimen 00 Pa, for the dical samples th an Oxford		
Special Equipment:			
Sample preparation equipment			
Measurements on the equipment done by:			Students Students after Introduction Students after extensive training Trained scientific service personal
Recent Publications, where this in was important (optional): Give citation		na eX (20	lyethylene/synthetic boehmite alumina nocomposites: PRESS Polymer Letters Vol.4, No.x 010) x–x, in print
Typical problems that may be sol instrument:	ved with this		orphological characterization emental analysis

## Methods, IMC, Mülhaupt